


<b>Search Notes</b>  	<b>Application/Control No.</b>  10594870	<b>Applicant(s)/Patent Under Reexamination</b>  TADMOR, YOAV
	<b>Examiner</b>  JASON HEIDEMANN	<b>Art Unit</b>  2624

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SEARCH NOTES		
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Search for NPL updated using GOOGLE SCHOLAR, IEEE using combinations of specific keywords ( blur, background, guassian)	10/14/2011	/JEH/
Search updated in East with text queries and subclasses using combinations of keywords such as (imag\$4, blur, background, guassian) - See attached Search History	10/14/2011	/JEH/
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